

Structure électronique d'un biplan de graphène couplage ab initio – liaisons fortes

L.Magaud

Institut Néel, CNRS-UJF, Grenoble,

CIMENT

phynum project

France

IDRIS



IOSCIENCES GRE

Rhône Alpes

Outline

1. Interface graphène – Face Si de SiC

- Données expérimentales
- Plan tampon



 $6\sqrt{3x6}\sqrt{3}$ R30 (>1300 atomes) approche DFT (VASP) potentiel classique EDIP : C sp² et sp³ + Si-C et C-C

- 2. Biplan de graphène tourné
 - Données expérimentales
 - Calculs ab initio
 - Liaisons fortes
- **3. Conclusion et futur : croissance**

Introduction : Methods - technical details

DFT calculations:



Scanning tunneling microscope :



Home made UHV- STM 6H SiC (0001) and (000-1), n doped

Si flux at 850 °C progressive annealing (900 -> 1100 °C)

F.Hiebel, F.Varchon, P.Mallet, J.-Y.Veuillen

DFT + GGA pseudo potential + plane wave large supercell (>1200 atoms)

F.Varchon, F.Hiebel, L.Magaud IN and PHYNUM

Le graphène :



exfolié (Geim Novoselov, Kim) sur SiC (de Heer) sur métaux

1 plan de C en réseau nid d'abeille



a=b, θ=120°

Réseau de Bravais hexagonal



The Einstein Approximation #1424



'The Einstein Approximation' - Season 3, Episode 14

Sheldon's search for the answer to a physics problem leads him to work at the Cheesecake Factory with Penny.



Faces polaires des polytypes hexagonaux de SiC



Si face : strong interaction with substrate => buffer layer

Common cell graphene – SiC 6√3x6√3 R30



√3x√3 R30 F.Varchon et al., PRL. 99, 126805, (2007) A.Mattausch et al. PRL99, 076802, (2007) G D'

W.Chen et al Surf.Sci.596,176 (2005) E.Rollings et al J.Phys.Chem. Sol 67, 2172 (2006) F.Owman et al. Surf. Sci. 369, 126 (1996) M.-H.Tsai et al. Phys. Rev. B45, 1327 (1992) Th.Seyller et al Surf. Sci. 600, 3906 (2006) E.K.Emtsev et al. Mater. Sci. Forum 556-557, 525 (2007)

6√3x6√3 R30

F.Varchon et al., Phys.Rev.B 77, 235412

(2008)

S.Kim et al. Phys. Rev. Lett 100.176802 (2008)

Nanostructuration of the first C layer

Ab initio

F.Varchon et al, Phys. Rev. B (2008)





- mosaic pattern with local $\sqrt{3x}\sqrt{3R30}$

- apparent 6X6 reconstruction
- Corrugation : 1.2 Å (STM : 1-1.5 Å)

Image STM (0.2 V, 300 K)

P.Mallet et al., Phys Rev B74, 041403 (R) (2007)



10 × 10 nm²



grains : √3x√3R30 matching regions covalent bond
frontier : not in register no bond atom higher

Nanostructuration of the first C layer



VASP : 1316 atomes : 13x13 graphène sur 4 biplans de SiC en $6\sqrt{3x6}\sqrt{3}$ R30

Un an de calcul sur une SGI 350 avec 8 processeurs (6 mois réels)

deuxième plan de C : limite SiC à 2 biplans essais de modification des états d'interface, de diffusion, de croissance trop long

SIESTA

Origins of anomalous electronic structures of epitaxial graphene on silicon carbide

Seungchul Kim,¹ Jisoon Ihm,¹ Hyoung Joon Choi,² and Young-Woo Son^{1,*}





E.Lampin et al, J.Appl. Phys. 107, 103514 (2010) C sp² et sp³ + liaisons Si-C et C-C G.Lucas et al JPCM 22, 035802 (2010)







EDIP : environment dependent interatomic potential

E.Lampin, C.Priester, C.Krzeminski, LM J.Appl. Phys. 107, 103514 (2010)

M.Z.Bazant, E.Kaxiras, PRL 77, 4370 (1996) pour Si G.Lucas, M.Bertolus, L.Pizagalli JPCM 22, 035802 (2010) adaptation pour SiC

$$E = \sum_{i} E_{i},$$

$$E_{i} = \sum_{j \neq i} V_{2}(\vec{r}_{i}, \vec{r}_{j}, Z_{i}) + \sum_{j \neq i} \sum_{k \neq i, k > i} V_{3}(\vec{r}_{i}, \vec{r}_{j}, \vec{r}_{k}, Z_{i}).$$

$$Z_{i} = \sum_{m \neq i} f(r_{im}) \qquad f(\mathbf{r}) = \begin{cases} 1, & r < c \\ \exp\left[\alpha / \left(1 - \left(\frac{a - c}{r - c}\right)^{3}\right)\right] \Delta(r), & c < r < a \\ 0, & r > a. \end{cases}$$

$$\begin{aligned} V_{2}(r_{ij}, Z_{i}) &= A\left[\left(\frac{B}{r_{ij}}\right)^{\rho} - p(Z_{i})\right] \exp\left(\frac{\sigma}{r_{ij} - a}\right) \\ p(Z) &= \exp(-\beta Z^{2}) \\ V_{3}(\vec{r}_{ij}, \vec{r}_{ik}, Z_{i}) &= g(r_{ij})g(r_{ik})h(l_{ijk}, Z_{i}) \\ l_{ikj} &= \cos \theta_{ijk} = \vec{r}_{ij} \cdot \vec{r}_{ik}/r_{ij}r_{ik} \\ g(r) &= \exp\left(\frac{\gamma}{r - a}\right) \\ \text{Stillinger-Weber} \\ h(l, Z) &= \lambda[(1 - \exp(-Q(Z)(l + \tau(Z))^{2})) \\ &+ \eta Q(Z)(l + \tau(Z))^{2}], \\ \omega(Z)^{-2} &= Q(Z) = Q_{0}\exp(-\mu Z) \\ \omega(Z) \text{ force de l'interaction} \\ \tau(Z) &= u_{1} + u_{2}(u_{3}\exp(-u_{4}Z) - \exp(-2u_{4}Z)) \end{aligned}$$

13 paramètres pour Si

SiC

A: garde Si optimise C Si-C moyenne + correction $\Delta(r) = \begin{cases} 1, & r < c \\ \exp\left(\frac{\alpha}{1-x^{-3}}\right), & c < r < a - \delta \\ 0, & r > a - \delta, \end{cases}$

δ=0.3 Å

B: tout réoptimisé

$$f(\mathbf{r}) = \begin{cases} 1, & r < c \\ \exp\left[\alpha / \left(1 - \left(\frac{a-c}{r-c}\right)^3\right)\right] \Delta(\mathbf{r}) & c < r < a \\ 0, & r > a. \end{cases}$$

$$V_2(r_{ij}, Z_i) = A\left[\left(\frac{B}{r_{ij}}\right)^{\rho} - p(Z_i)\right] \exp\left(\frac{\sigma}{r_{ij} - a}\right) \quad \Delta(\mathsf{rij})$$

 $V_3(\vec{r}_{ij}, \vec{r}_{ik}, Z_i) = g(r_{ij})g(r_{ik})h(l_{ijk}, Z_i)\Delta(\mathsf{rij}) \Delta(\mathsf{rik})$

13X13 graphène sur $6\sqrt{3}x6\sqrt{3}$ R30 SiC (6 biplans)

biplan du bas gelé gradients conjugués

Fait varier la distance initiale plan de graphène – SiC de 1.5 à 3 Å par pas de 0.01 Å



Pré-relaxation du graphène : descend les C qui sont proches voisins de Si





Distance C-C dans le plan

2. C Face : Rotated bilayers

Van Bommel 1975

Weak interaction : no long range order for growth no Bernal stacking (twisted layers)



 $\sqrt{13} \times \sqrt{13} \text{ R} \pm 46.1^{\circ}$ commensurate with SiC

J. M. B. Lopes dos Santos et al., PRL 99, 256802 (**2007**) S. Latil et al., Phys. Rev B76, 201402(R) (**2007**) S.Shallcross et al, Phys. Rev. Lett. 101, 056803 (2008) – – AB bilayer •••••Monolayer ____ Twisted bilayer



Twist preserves linear dispersion

J. Hass et al., PRL 100, 125504 (2008)

2. Rotated bilayers: renormalisation of the velocity

L.Magaud, D.Mayou, G.Trambly de Laissardière

Ab initio (VASP) => periodic system Common cell for two layers rotated by θ



ab initio calculation + TB fit: small angles/ shift / asymmetric bilayer

Small angles (6,7) θ=5.08°

TB scheme

$$V_{pp\pi} = -\gamma_0 \exp\left(q_\pi \left(1 - \frac{d}{a}\right)\right)$$
$$V_{pp\sigma} = \gamma_1 \exp\left(q_\sigma \left(1 - \frac{d}{a_1}\right)\right) \text{ with } \frac{q_\sigma}{a_1} = \frac{q_\pi}{a}$$

 γ_0 = 2.7 eV, γ_1 =0.48 eV a=1.42 Å a1=3.35Å

fitted on AA, AB, (1,3) et (1,4)



3. Rotated bilayers: renormalisation of the velocity



G.Trambly, D.Mayou, L.Magaud, ArXiv : 0904.1233 NanoLetters 10, 804 (2010)

Lopez dos Santos et al ,PRL 99, 256802 (2007)



First regime :

- two decoupled graphene layers
- no change of velocity



Second anf third regime :

- Renormalization of velocity
- Two coupled graphene layers



Single Layer Behavior and Its Breakdown in Twisted Graphene Layers

A. Luican¹, Guohong Li¹, A. Reina², J. Kong³, R. R. Nair⁴, K. S. Novoselov⁴, A. K. Geim^{4,5}, E.Y. Andrei¹



Twisted layers from growth on Ni STS LL

 θ >20° decoupling 3< θ <20° renormalisation of velocity θ <3° van Hove singularity and localisation

third regime :







Conclusion

- <u>Si face</u>
- strong coupling
- 1rst layer = bufferlayer



E.Lampin et al, J.Appl. Phys. 107, 103514 (2010)

<u>C - face</u>

- weak coupling : passivation by surface reconstruction

- graphene = 1^{rst} C layer
- no epitaxy : rotated grains
- twist : from decoupling to localization





Collaborations :



STM P.Mallet, J-Y.Veuillen, F.Hiebel, F.Varchon

Theory LM, F.Varchon, D.Mayou, F.Hiebel, G.Trambly de Laissardière (Cergy-Pontoise) Driss Mouhamadou, Quentin Stainer

Fundings : ANR Blanche GRAPHSIC ANR P3N NANOSIM_GRAPHENE Region : CIBLE 2007 and CIBLE 2008, Cluster recherche Nanoscience Fundation grenoble : DISPOGRAPH





Growth

N.Camara et al, Appl. Phys. Lett. 93, 263102 (2008)



The substrate SiC

SiC : large band gap semiconductor

Si – C bilayers similar to C bilayers or Si bilayers along the (111) axis in diamond structure



DOS totale et partielles SiC 4H volume







 $\boldsymbol{\theta}$: rotation angle between two graphene layers a lattice parameter

• period of the superlattice (moiré)

 $D = a/(2\sin(\theta/2))$

•Angle ϕ between the moiré superlattice and graphene

φ= 30°-(θ/2)



F.Varchon et al, PRB 77, 235412 (2008)

Impact on atomic contrast



F.Varchon et al., PRB 77, 165415 (2008)

We observe, in a range of small biases (below and above E_F):

 honeycomb pattern (or a significantly reduced A/B site asymmetry) on the Moire superstructure

 triangular pattern on the flat region (bernal stacking)

Valuable indication that a single layer-like behavior can be found on rotated graphene layers.

S. Latil et al., Phys. Rev B76, 201402(R) (2007)

second C layer = graphene with soft ripples

Ab initio

STM image (0.2 V, 300 K),

P.Mallet et al., Phys Rev B74, 041403 (R) (2007)



Corrugation : 0.5 Å (STM : 0.2 – 0.4 Å), roughly follows buffer layer geometry, generates soft 6x6 ripples no C-C bond

graphene decoupled from the substrates thanks to the buffer layer





6R3 = complex model but actual interface even more complex

disorder adatoms at interface



5.6 x 5.6 nm², +0.2 V

Graphene on Ru (0001)



Marchini et al PRB 76, 075429 (2007)

STM

50x40 A

1mA, -0.05\

Wang et al, Phys. Chem. Chem. Phys. 10, 3530 (2008)